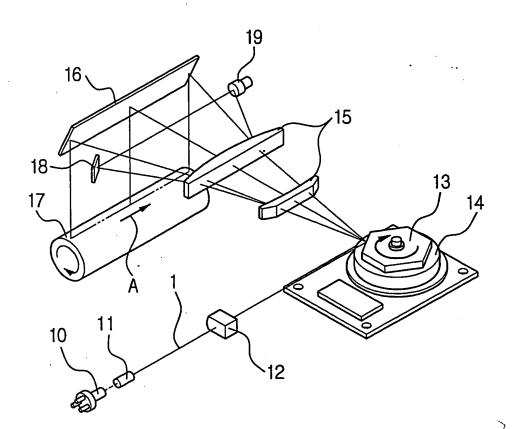
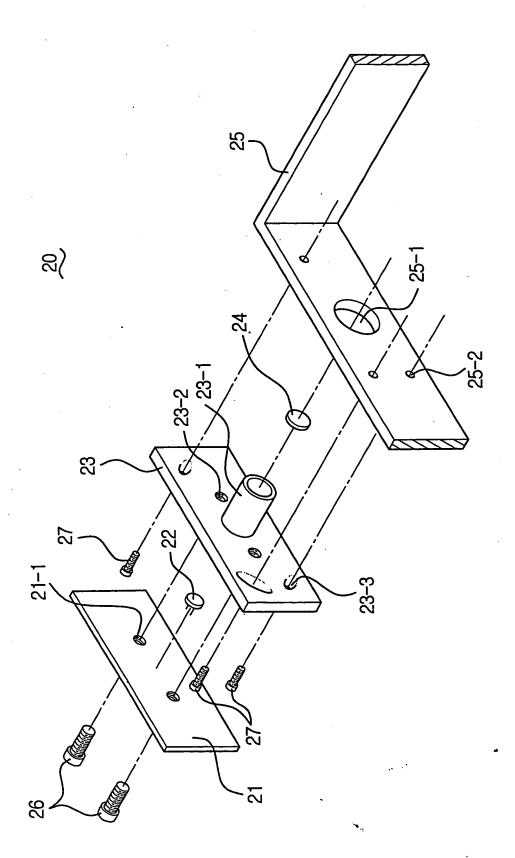
TITLE: SUB-SCANNING INTERVAL ADJUSTING APPARATUS FOR MULTI-BEAM SCANNING UNIT

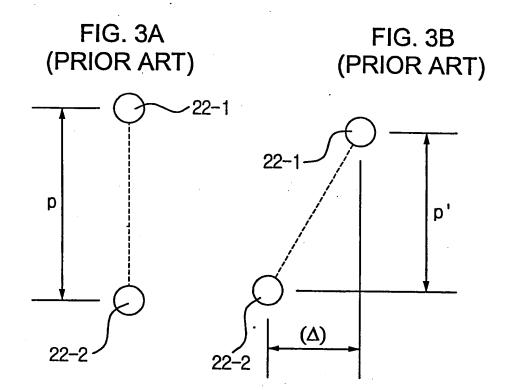
INVENTORS: Jae-hwan YOO SERIAL NO.: To be assigned DOCKET NO.: 1349.1218 CIP

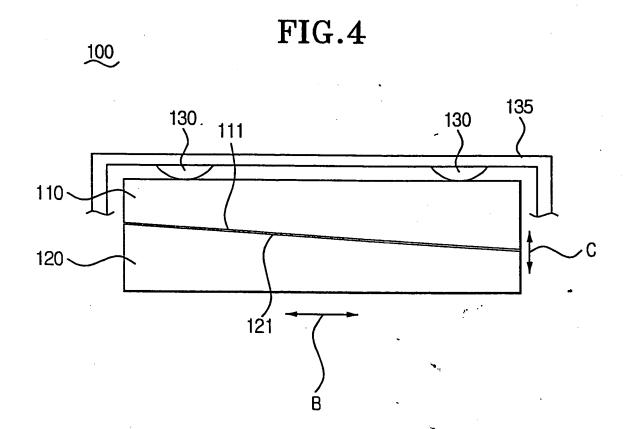
FIG.1 (PRIOR ART)





INVENTORS: Jae-hwan YOO SERIAL NO.: To be assigned DOCKET NO.: 1349.1218 CIP





FOR MULTI-BEAM SCANNING UNIT INVENTORS: Jae-hwan YOO SERIAL NO.: To be assigned DOCKET NO.: 1349.1218 CIP

FIG.5

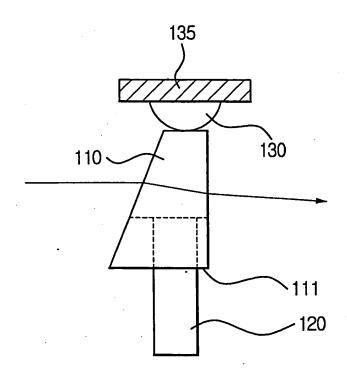
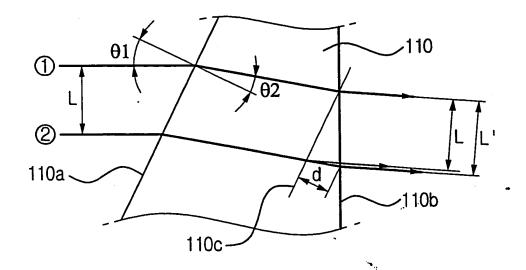


FIG.6



FOR MULTI-BEAM SCANNING UNIT INVENTORS: Jae-hwan YOO SERIAL NO.: To be assigned DOCKET NO.: 1349.1218 CIP

FIG.7A

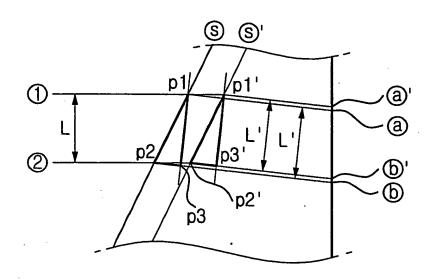
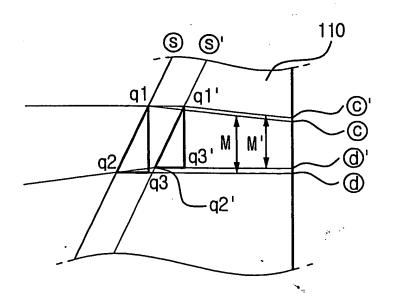


FIG.7B



FOR MULTI-BEAM SCANNING UNIT INVENTORS: Jae-hwan YOO SERIAL NO.: To be assigned DOCKET NO.: 1349.1218 CIP

FIG.8



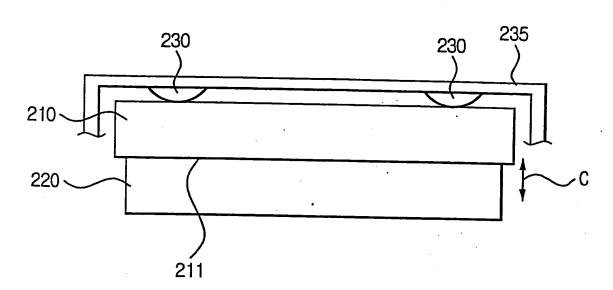
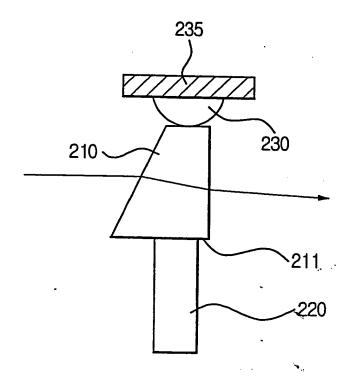


FIG.9



TITLE: SUB-SCANNING INTERVAL ADJUSTING APPARATUS FOR MULTI-BEAM SCANNING UNIT INVENTORS: Jae-hwan YOO SERIAL NO.: To be assigned DOCKET NO.: 1349.1218 CIP

FIG. 10

